## Notice of References Cited Application/Control No. 10/605,762 Examiner Vincent T. Tran Applicant(s)/Patent Under Reexamination CHEN ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2004/0030876	02-2004	Qureshi et al.	713/1
*	В	US-5,768,568	06-1998	Inui et al.	710/16
*	С	US-2004/0243534	12-2004	Culter et al.	707/001
*	D	US-2004/0044888	03-2004	Nalawadi et al.	713/002
*	Е	US-6,453,461	09-2002	Chaiken, Craig L.	717/124
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	K	US-			
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	x	

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